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PCN Date: 5/8/2014 Effective Date: 8/14/2014									
Title: Si7005 / Si7015 Assembly Site Addition - ASEKR									
Originator: Bill Simcoe Phone: 1-512-532-5810 Dept: Marketing									
Customer Contact:Kathy HaggarPhone:1-512-532-5261Dept:Sales									
PCN Type:									
Datasheet Foundry Packing									
Product Revision Assembly Labeling									
Discontinuance Test Other									
Last Order Date: Not Applicable									
PCN Details									
Description of Change: Silicon Labs is pleased to announce the successful qualification of ASEKR (Advanced Semiconductor Engineering Korea) as an additional assembly site for the Si7005 and Si7015 products. ASEKR is an existing assembly and test site for Silicon Labs, and is certified to ISO9001, ISO14001, and ISO/TS16949.									
As of the effective date of the PCN, Silicon Labs will fulfill orders from either of the qualified assembly suppliers.									
Reason for Change:									
Increase assembly capacity and ensure dual sourcing. Impact on Form, Fit, Function, Quality, Reliability:									
There is no change to fit, function, quality, or reliability of these devices.									
Si7005 and Si7015 devices assembled at ASEKR will have a lower package thickness than those devices that are currently in production. The package thickness for devices assembled at ASEKR is already given in the current Si7005 and Si7015 datasheets as "Package Variant B".									
Product Identification: This Change Notification applies to the following ordering part numbers: Si7005-B-FMR Si7005-B-FMR Si7005-B-GMR Si7005-B-GMR Si7005-B-GMR Si7015-A10-FMR Si7015-A10-FMR Si7015-A10-GMR Si7015-A10-GM1R The 7 th character of the date code on the shipping label identifies the assembly site for Si7005 and Si7015 devices. The codes are listed below: 7 : Assembled at Sencio (currently in production) 0 : Assembled at ASEKR									

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Qualification Samples:

Samples are available upon request. Contact your local Silicon Labs sales representative. A list of Silicon Labs sales representatives is available at <u>www.silabs.com</u>

Specific conditions of acceptance of this change will be considered on a case by case basis if written notice is submitted within 30 days of this notice. To request further data or inquire about this notification, please contact your local Silicon Labs sales representative. A list of Silicon Labs sales representatives is available at www.silabs.com.

In some cases rejection of a change notice may impact Silicon Labs product pricing, delivery, quality, or reliability.

Customers may approve early PCN acceptance by completing the information below:

Early Acceptance: Date: _____

Name: _____

Company:

Email your early Acceptance approval to: <u>katherine.haggar@silabs.com</u>

Qualification Data:

Please see below report.



Rev. D

Qualification Report

Si7005 Qualification Report

W7101F1 Product Qualification Plan and Report

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Part Rev B, UMC Fabrication, ASEKr Assembly except as noted								
Test Name	Test Condition	Qualification	Start	or End	Notes	Summary	Status	
Test Group A - A	cœlerated Environment Stress	Tests						
HAST	JA110		Q34728	0/80	1,3			
	130°C,85%RH	3 lots, N=>77	Q34737	0/79	1,3	3 lots		
	Vcc=3.6V, 96 hours		Q34733	0/77	1,3	0/236	Pass	
UHAST	JA110		Q34731	0/80	1,3			
	130°C,85%RH	3 lots, N=>77	Q34736	0/80	1,3	3 lots		
	Vcc=3.6V, 96 hours		Q34732	0/80	1,3	0/240	Pass	
Temp Cycle	JA104		Q34738	0/79	1			
	Cond C: -65°C to 150°C	3 lots, N=>77	Q34734	0/80	1	3 lots		
	500 cycles		Q34730	0/80	1	0/239	Pass	
HTSL	JA103		Q34739	0/50	1			
	150°C, 1000hr	3 lots, N=>45	Q34735	0/50	1	3 lots		
			Q34729	0/50	1	0/150	Pass	
Test Group B - A	ccelerated Lifetime Simulation	Tests						
HTOL	JA108		Q31657	0/83				
	125°C, Dynamic	3 lots, N=>77	Q32460	0/84		3 lots		
	Vcc=3.6V, 1000 hours		Q32872	0/81		0/248	Pass	
ELFR	AEC-Q100-008		Q31940	0/821				
	125°C, Dynamic	3 lots, N=>800	Q32228	0/800		3 lots		
	Vcc=3.6V, 48 hours		Q33040	0/858		0/2479	Pass	
LTOL	JA108							
	-10°C, Dynamic	1 lot, N=>32	Q32571	0/34		1 lot		
	Vcc=3.6V, 1000 hours					0/34	Pass	
Test Group E - El	ectrical Verification							
ESD-HBM	AEC-Q100-002							
		1 lot, N=>3	Q32115	0/3	3000 V	1 lot		
						0/3	Pass	
ESD-MM	AEC-Q100-003							
		1 lot, N=>3	Q32114	0/3	300 V	1 lot		
						0/3	Pass	
ESD-@M	AEC-Q100-011							
		1 lot, N=>3	Q32116	0/3	750 V	2 lots		
			Q32666 ²	0/3	750 V	0/6	Pass	
Latch Up	AEC-Q100-004							
	±200mA	1 lot, N=>6	Q32200	0/6	85 ⁰C	2 lots		
			Q32113	0/6	25 ⁰C	0/12	Pass	

Notes:

1. Parts are Pre-conditioned at MSL2/260⁴C

2. With filter

3. For post-stress testing, the long term drift specification of table 4 (datasheet) applies. For tests involving humidity stresses (HAST, UHAST and PC) the bake and rehydration procedure of section 4.6 (datasheet) is used prior to test.

This report appies to the following part numbers :							
S17005-B-GM/R	Si7005-B-FM/R	Si7005-B-GM1/R	S17005-B-FM1/R	Si7015-B-GM/R			
S17015-B-FM/R	Si7015-B-GM1/R	Si7015-B-FM1/R					

Approved by: Noel Arguello

Prepared on: 7-May-14

W7206F1 Process Change Notice Form rev AM

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